



## N-Channel Enhancement MOSFET

### Features

- Drain-Source Breakdown Voltage  $V_{DS}$  50 V
- Drain-Source On-Resistance  
 $R_{DS(ON)}$  1.3 $\Omega$ , at  $V_{GS}= 10V$ ,  $I_D= 0.2A$   
 $R_{DS(ON)}$  1.4 $\Omega$ , at  $V_{GS}= 5V$ ,  $I_D= 0.2A$   
 $R_{DS(ON)}$  1.6 $\Omega$ , at  $V_{GS}= 2.75V$ ,  $I_D= 0.2A$
- Continuous Drain Current at  $T_A=25^\circ C$   $I_D = 0.3A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

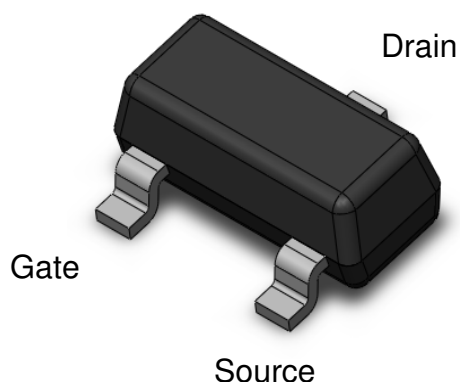
### Applications

- DC/DC Converter
- Load Switch
- LCD Display inverter
- Power Management

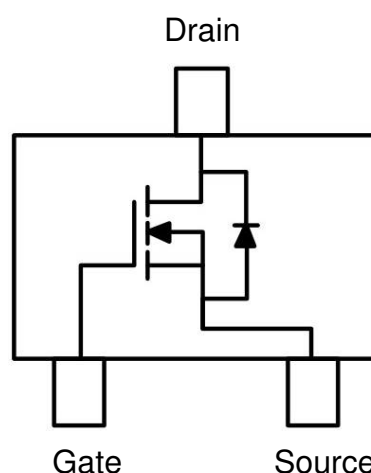
### Description

The CTL0035NS-R3 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance.

### Package Outline



### Schematic





CTL0035NS-R3

## N-Channel Enhancement MOSFET

### Absolute Maximum Rating at 25°C

Symbol	Parameters	Test Conditions	Min	Notes
V <sub>DS</sub>	Drain-Source Voltage	50	V	
V <sub>GS</sub>	Gate-Source Voltage	±20	V	
I <sub>D</sub>	Continuous Drain Current @T <sub>A</sub> =25°C	0.3	A	1
I <sub>DM</sub>	Pulsed Drain Current	1	A	1
P <sub>D</sub>	Total Power Dissipation @T <sub>A</sub> =25°C	0.36	W	2
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C	
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C	

### Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R <sub>θJA4</sub>	Thermal Resistance Junction-Ambient (t=10s)		--	350	--	°C /W	1,4



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Electrical Characteristics  $T_A = 25^\circ\text{C}$  (unless otherwise specified)

## Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$B_{V_{DS}}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	50	-	-	V	
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS} = 50V, V_{GS} = 0V$	-	-	1	$\mu A$	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	$\pm 100$	nA	

## On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = 10V, I_D = 0.2A$	-	1.3	3	$\Omega$	3
		$V_{GS} = 5V, I_D = 0.2A$	-	1.4	3.5	$\Omega$	
		$V_{GS} = 2.75V, I_D = 0.2A$	-	1.6	7	$\Omega$	
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu A$	0.7	---	1.5	V	3

## Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$C_{ISS}$	Input Capacitance	$V_{GS} = 0V,$ $V_{DS} = -25V$ $f = 1MHz$	-	42	-	pF	
$C_{OSS}$	Output Capacitance		-	15	-		
$C_{RSS}$	Reverse Transfer Capacitance		-	3	-		

## Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = 30V,$ $V_{GS} = 10V,$ $R_G = 6\Omega,$ $R_L = 103\Omega,$	-	4.63	-	ns	
$T_R$	Rise Time		-	18.9	-		
$T_{D(OFF)}$	Turn-Off Delay Time		-	6.8	-		
$T_F$	Fall Time		-	11.4	-		
$Q_G$	Total Gate Charge	$V_{DS} = 25V,$ $V_{GS} = 10V,$ $I_D = 0.22A$	-	7.03	-	nC	
$Q_{GS}$	Gate-Source Charge		-	1.84	-		
$Q_{GD}$	Gate-Drain Charge		-	0.65	-		

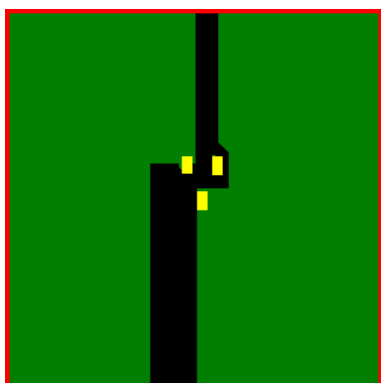


**Drain-Source Diode Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V <sub>SD</sub>	Body Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 0.44	-	0.8	1.4	V	
I <sub>SD</sub>	Body Diode Continuous Current		-	-	0.3	A	1

Note:

- 1. The power dissipation is limited by 150°C junction temperature.
- 2. Device mounted on a glass-epoxy board



FR-4  
25.4 × 25.4 mm .  
2 Oz Copper

Actual Size

- 3. The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 4. Thermal Resistance follow JESD51-3.



Typical Characteristic Curves

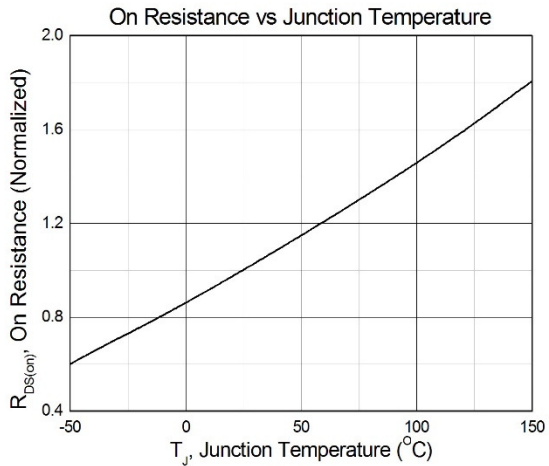


Figure 1

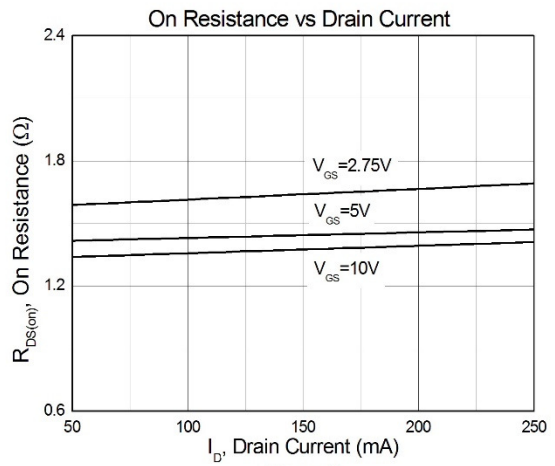


Figure 2

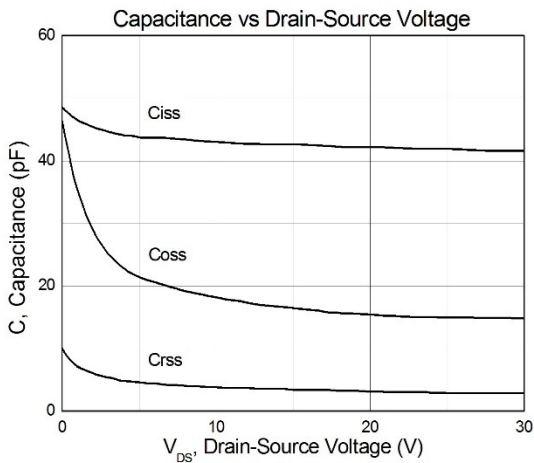


Figure 3

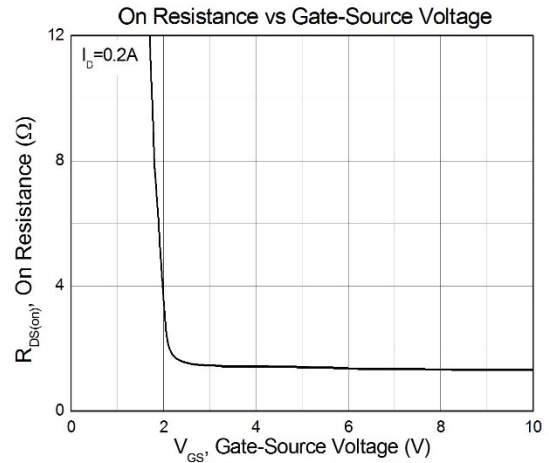


Figure 4

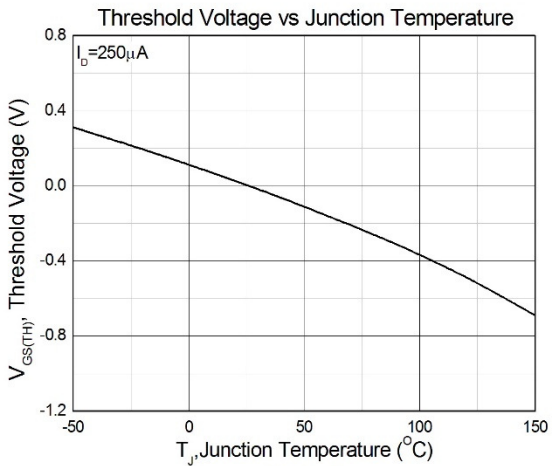


Figure 5

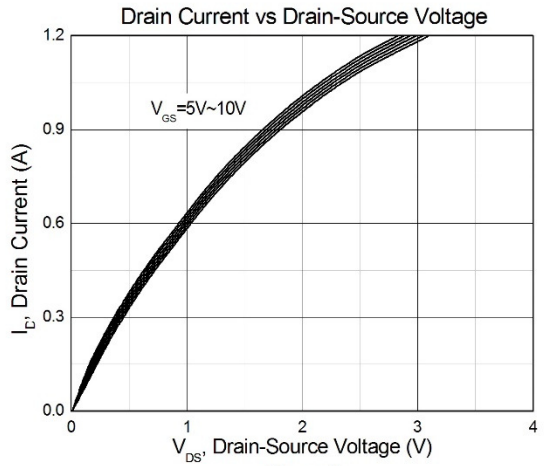
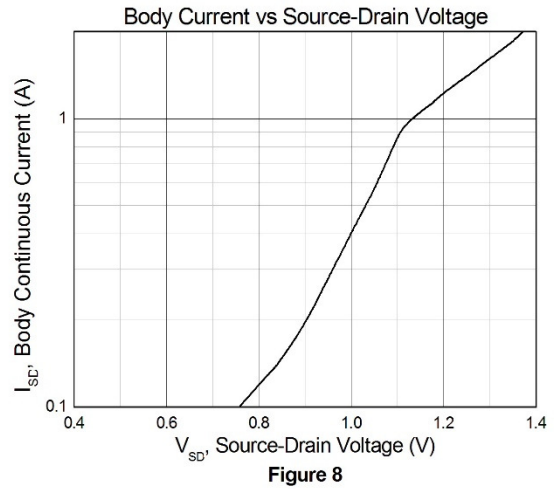
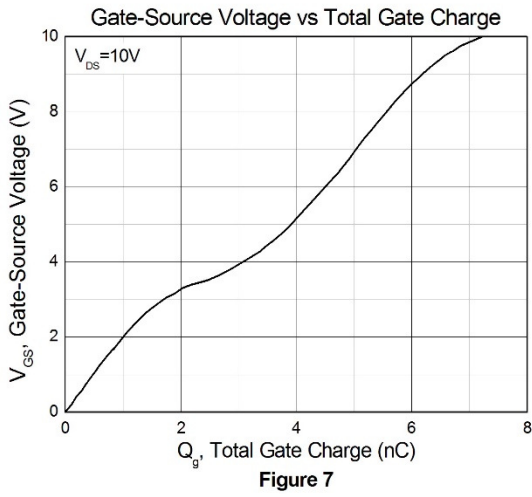


Figure 6





Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

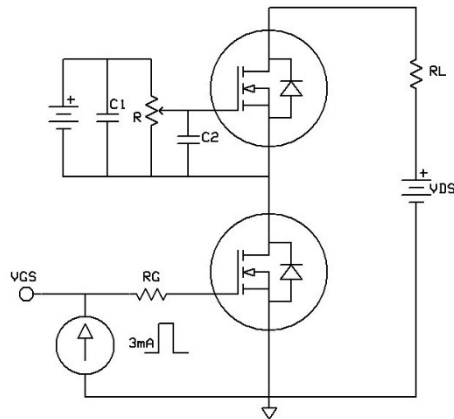


Figure 10: Gate Charge Waveform

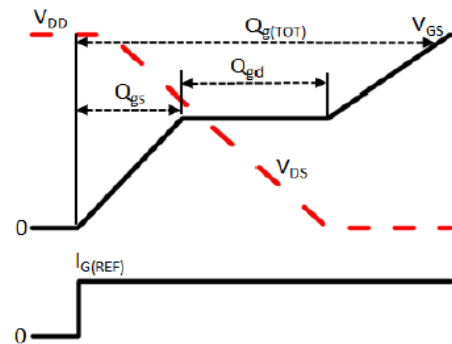


Figure 11: Switching Time Test Circuit

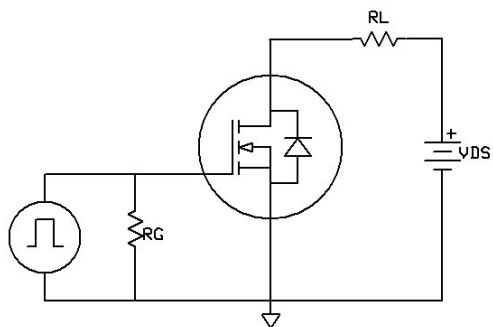
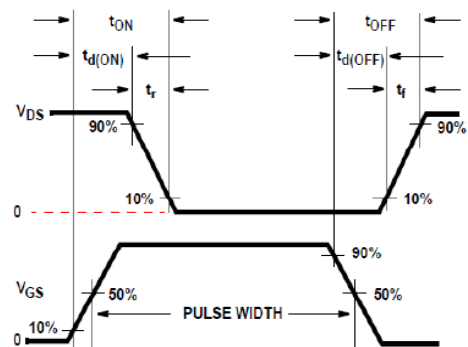
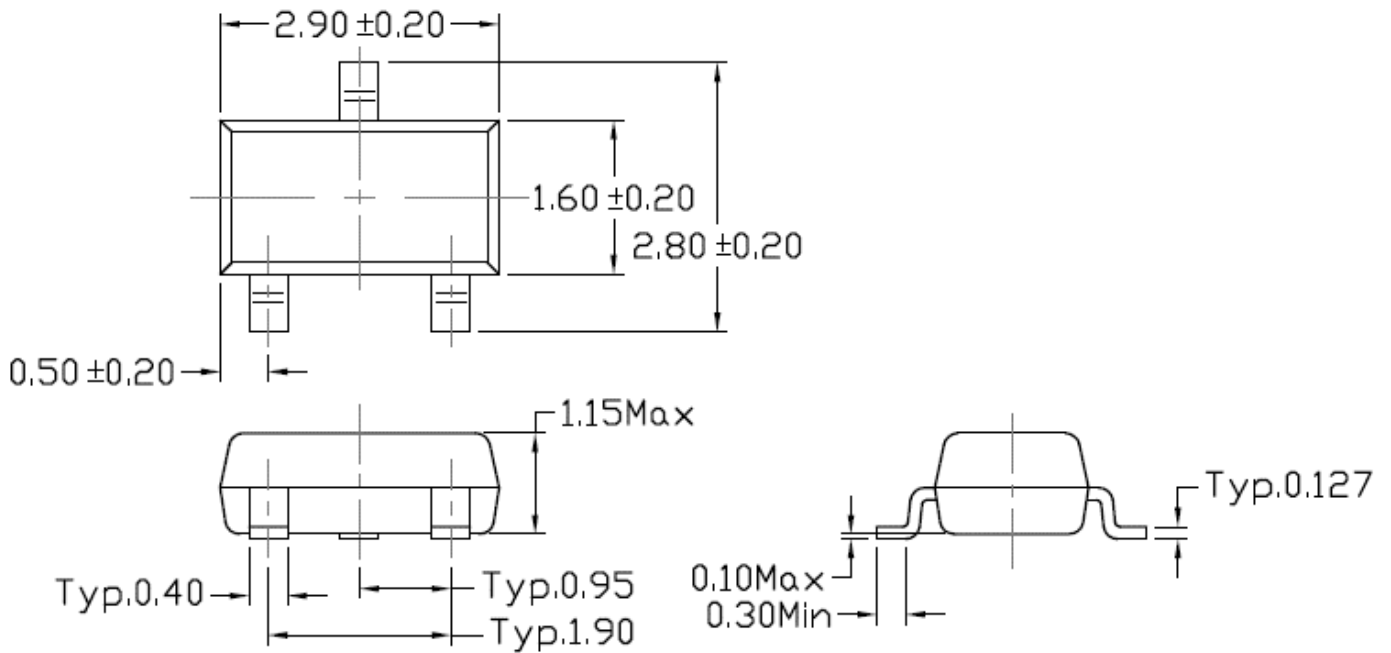


Figure 12: Switching Time Waveform

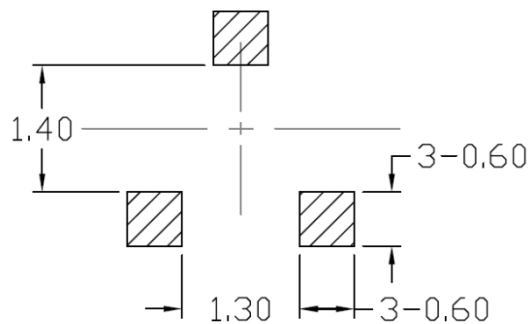




Package Dimension (SC-59)



Recommended pad layout for surface mount leadform



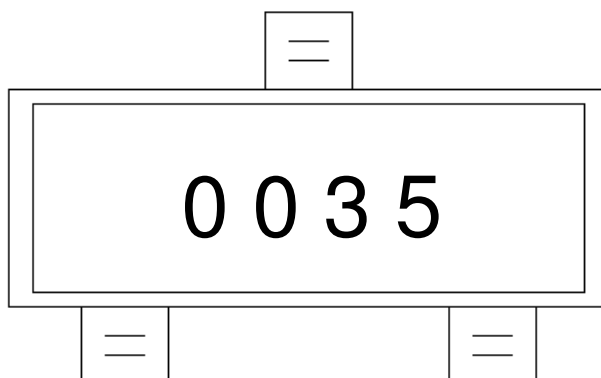




CTL0035NS-R3

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### Marking Information



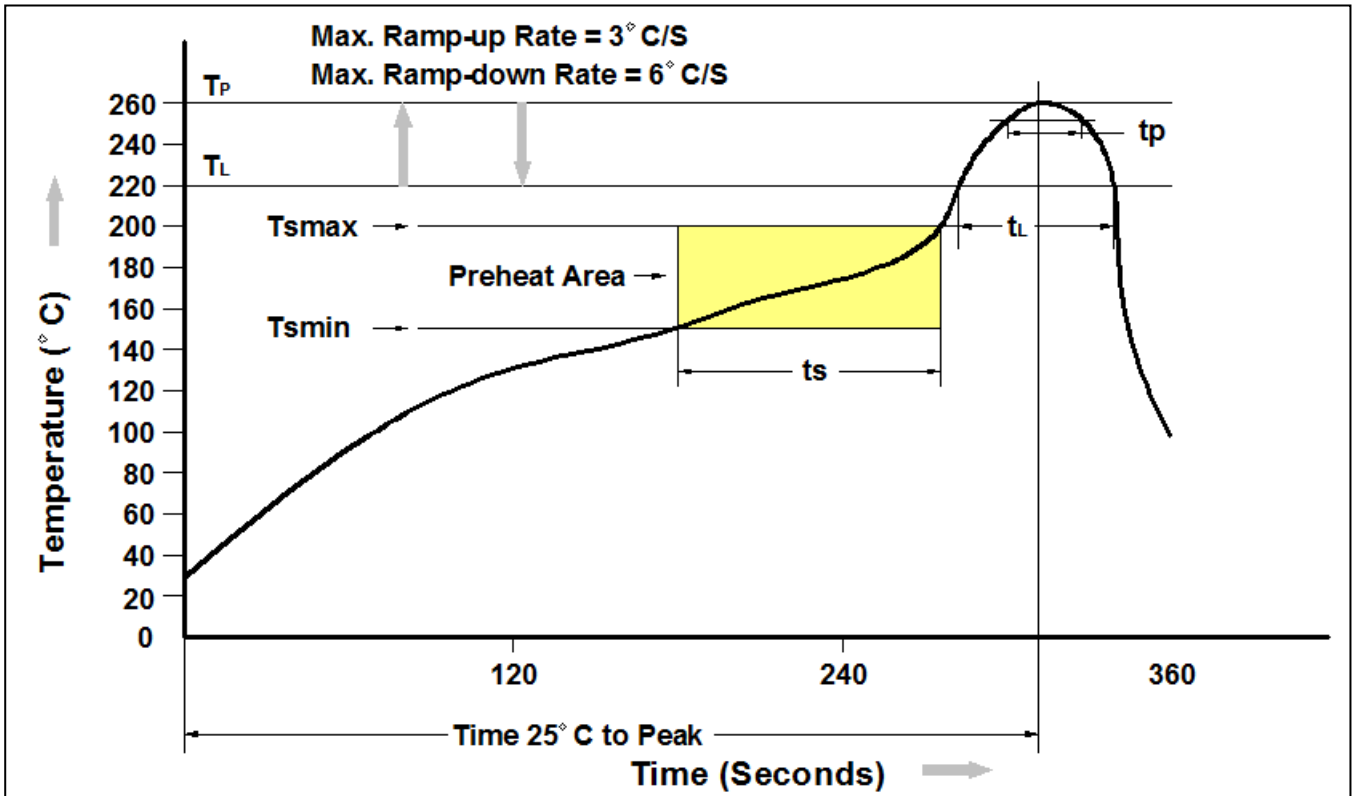
0035: Device Number

### Ordering Information

Part Number	Description	Quantity
CTL0035NS-R3	SC-59 Reel	3000 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T <sub>smin</sub> )	150 °C
Temperature Max. (T <sub>smax</sub> )	200 °C
Time (t <sub>s</sub> ) from (T <sub>smin</sub> to T <sub>smax</sub> )	60-120 seconds
Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )	3 °C/second max.
Liquidous Temperature (T <sub>L</sub> )	217 °C
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60 – 150 seconds
Peak Body Package Temperature	260 °C +0 °C / -5 °C
Time (t <sub>P</sub> ) within 5 °C of 260 °C	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6 °C/second max
Time 25 °C to Peak Temperature	8 minutes max.



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